



ESD



TVS



MOS



LDO



Diode



Sensor



DC-DC

## Product Specification

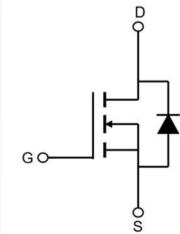
▶ Domestic Part Number	IRF1010ES
▶ Overseas Part Number	IRF1010ES
▶ Equivalent Part Number	IRF1010ES



EV is the abbreviation of name EVVO

## Feature

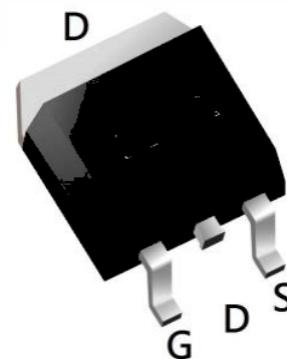
- 60V,80A
- $R_{DS\ (ON)} < 10m\ \Omega @ V_{GS}=10V$
- $R_{DS\ (ON)} < 14m\ \Omega @ V_{GS}=4.5V$
- Advanced Trench Technology
- Lead free product is acquired
- Excellent  $R_{DS\ (ON)}$  and Low Gate Charge



Schematic Diagram

## Application

- PWM applications
- Load Switch
- Power management



## ABSOLUTE MAXIMUM RATINGS ( $T_a=25^\circ C$ unless otherwise noted)

Parameter	Symbol	Value	Unit
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current ( $T_a = 25^\circ C$ )	$I_D$	80	A
Continuous Drain Current ( $T_a = 100^\circ C$ )	$I_D$	56	A
Pulsed Drain Current <sup>(1)</sup>	$I_{DM}$	232	A
Singel Pulsed Avalanche Energy <sup>(2)</sup>	$E_{AS}$	110	mJ
Power Dissipation	$P_D$	70	W
Thermal Resistance from Junction to Case	$R_{eJC}$	2.14	$^\circ C/W$
Junction Temperature	$T_J$	150	$^\circ C$
Storage Temperature	$T_{STG}$	-55~+150	$^\circ C$

**MOSFET ELECTRICAL CHARACTERISTICS( $T_a=25^\circ\text{C}$  unless otherwise noted)**

Parameter	Symbol	Test Condition	Min	Type	Max	Unit
<b>Static Characteristics</b>						
Drain-source breakdown voltage	$V_{(\text{BR})\text{DSS}}$	$V_{GS} = 0V, I_D = -250\mu\text{A}$	60	-	-	V
Zero gate voltage drain current	$I_{\text{DSS}}$	$V_{DS} = 60V, V_{GS} = 0V$	-	-	1	$\mu\text{A}$
Gate-body leakage current	$I_{GSS}$	$V_{GS} = \pm 20V, V_{DS} = 0V$	-	-	$\pm 100$	nA
Gate threshold voltage <sup>(3)</sup>	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.7	2.5	V
Drain-source on-resistance <sup>(3)</sup>	$R_{DS(\text{on})}$	$V_{GS} = 10V, I_D = 30\text{A}$	-	7.5	10	$\text{m}\Omega$
		$V_{GS} = 4.5V, I_D = 20\text{A}$	-	10	14	
Forward transconductance <sup>(3)</sup>	$g_{FS}$	$V_{DS} = 10V, I_D = 30\text{A}$	20	-	-	S
<b>Dynamic characteristics</b>						
Input Capacitance	$C_{iss}$	$V_{DS} = 25V, V_{GS} = 0V, f = 1\text{MHz}$	-	4400	-	pF
Output Capacitance	$C_{oss}$		-	210	-	
Reverse Transfer Capacitance	$C_{rss}$		-	190	-	
<b>Switching characteristics</b>						
Turn-on delay time	$t_{d(on)}$	$V_{DD} = 30V, I_D = 30\text{A}, R_L = 1\Omega$ $V_{GS} = 10V, R_G = 3\Omega$	-	7.1	-	ns
Turn-on rise time	$t_r$		-	5.3	-	
Turn-off delay time	$t_{d(off)}$		-	27.2	-	
Turn-off fall time	$t_f$		-	6.2	-	
Total Gate Charge	$Q_g$	$V_{DS} = 30V, I_D = 30\text{A},$ $V_{GS} = 10V$	-	77	-	nC
Gate-Source Charge	$Q_{gs}$		-	9	-	
Gate-Drain Charge	$Q_{gd}$		-	23	-	
<b>Source-Drain Diode characteristics</b>						
Diode Forward voltage <sup>(3)</sup>	$V_{DS}$	$V_{GS} = 0V, I_S = 30\text{A}$	-	-	1.2	V
Diode Forward current <sup>(4)</sup>	$I_S$		-	-	80	A
Body Diode Reverse Recovery Time	$t_{rr}$	$T_J = 25^\circ\text{C}, I_F = 30\text{A}, dI/dt = 100\text{A}/\mu\text{s}$		29		ns
Body Diode Reverse Recovery Charge	$Q_{rr}$	$T_J = 25^\circ\text{C}, I_F = 30\text{A}, dI/dt = 100\text{A}/\mu\text{s}$		45		nc

**Notes:**

1. Repetitive Rating: pulse width limited by maximum junction temperature
2. EAS Condition:  $T_J = 25^\circ\text{C}, V_{DD} = 20V, R_G = 25\Omega, L = 0.5\text{mH}, I_{AS} = 21\text{A}$
3. Pulse Test: pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$
4. Surface Mounted on FR4 Board,  $t \leq 10$  sec

## Test Circuit

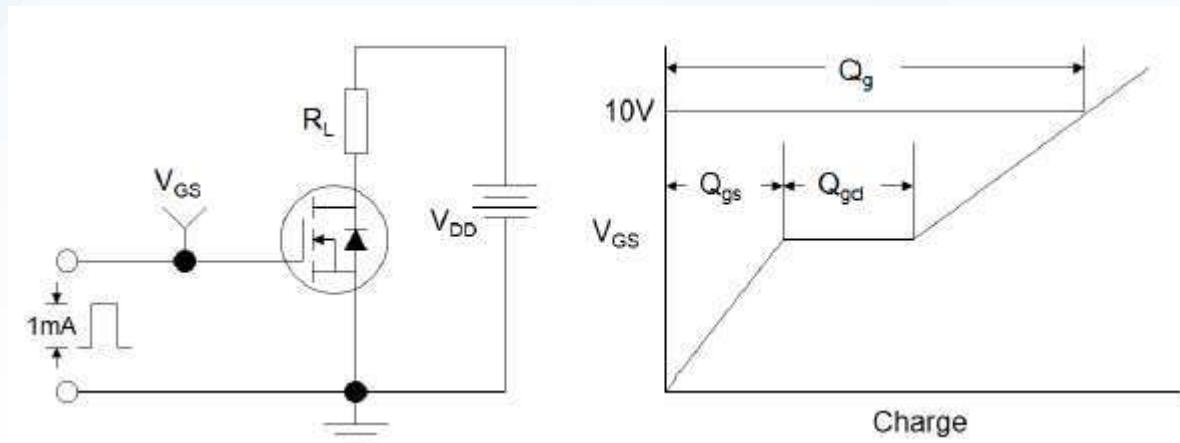


Figure1:Gate Charge Test Circuit & Waveform

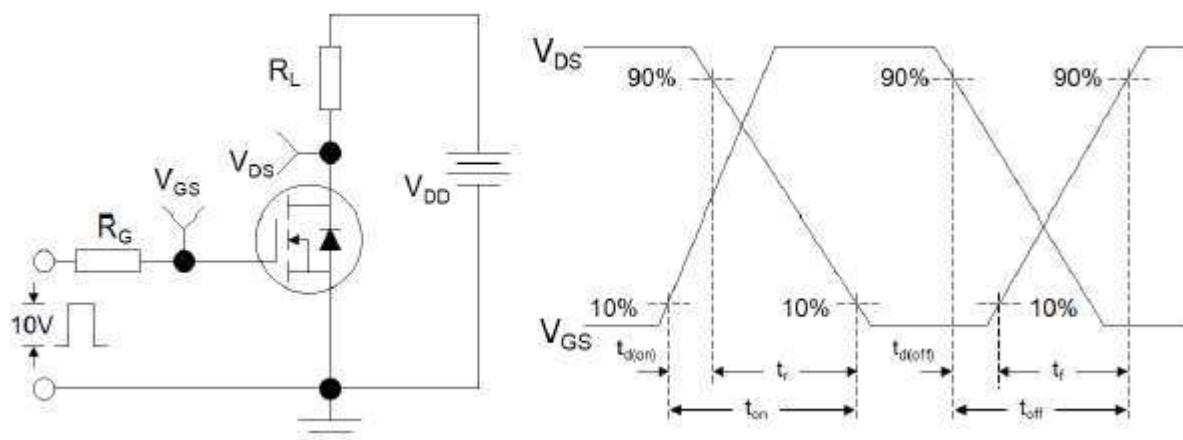


Figure 2: Resistive Switching Test Circuit & Waveforms

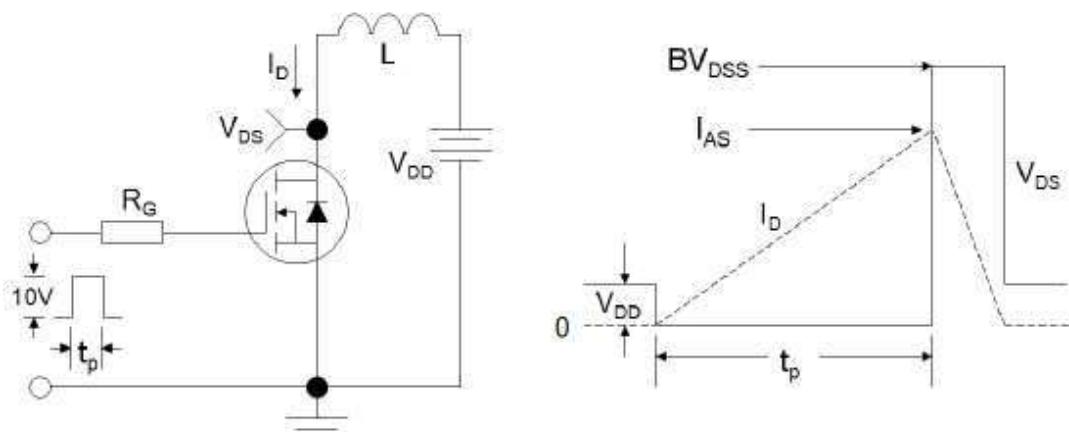
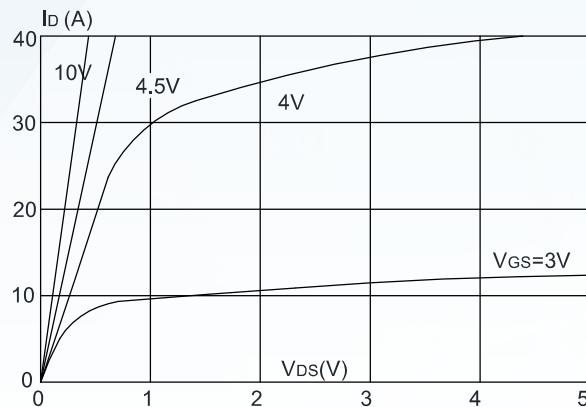
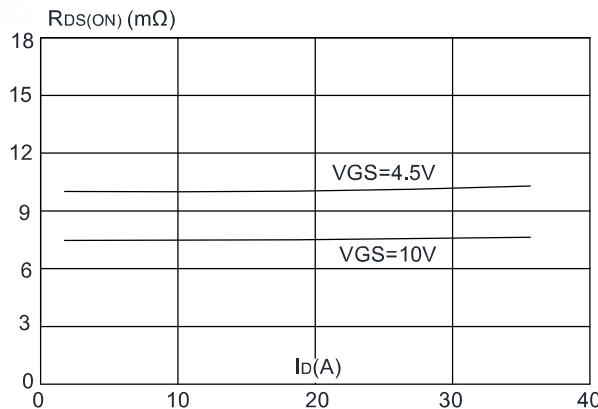


Figure 3:Unclamped Inductive Switching Test Circuit & Waveforms

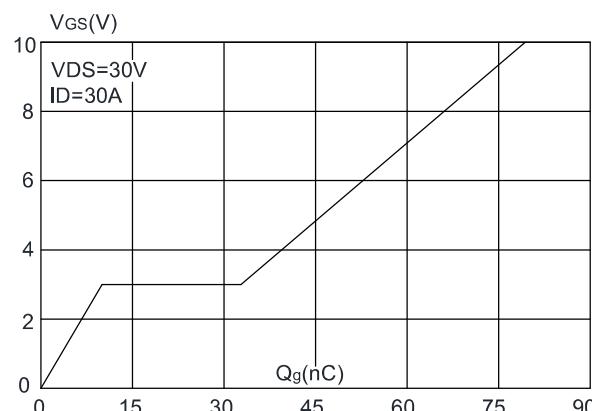
**Figure 1:** Output Characteristics



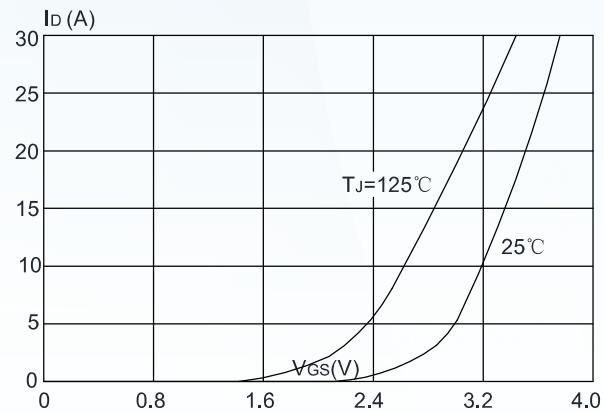
**Figure 3:** On-resistance vs. Drain Current



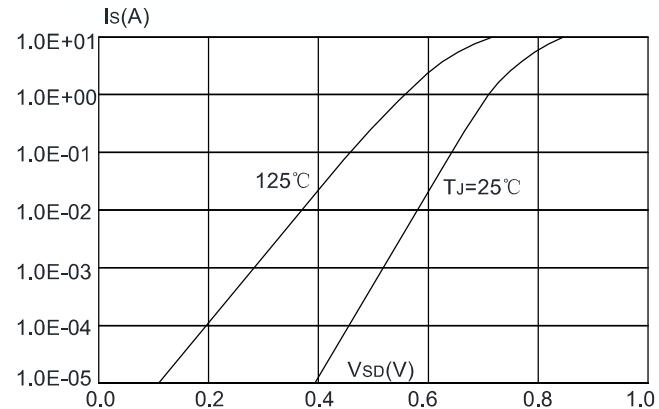
**Figure 5:** Gate Charge Characteristics



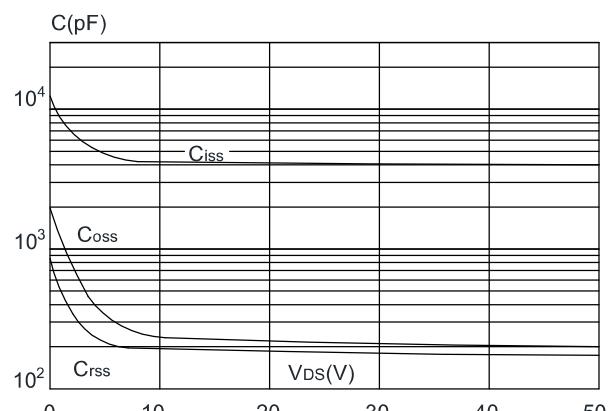
**Figure 2:** Typical Transfer Characteristics



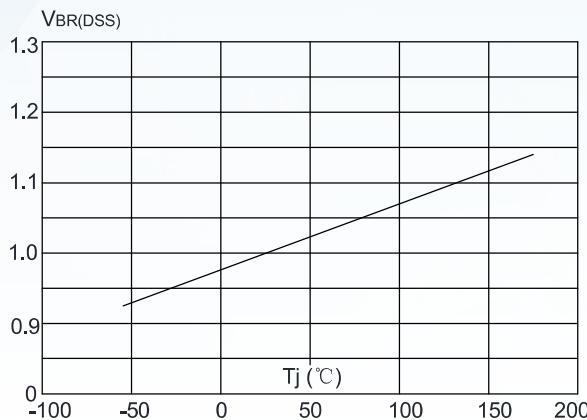
**Figure 4:** Body Diode Characteristics



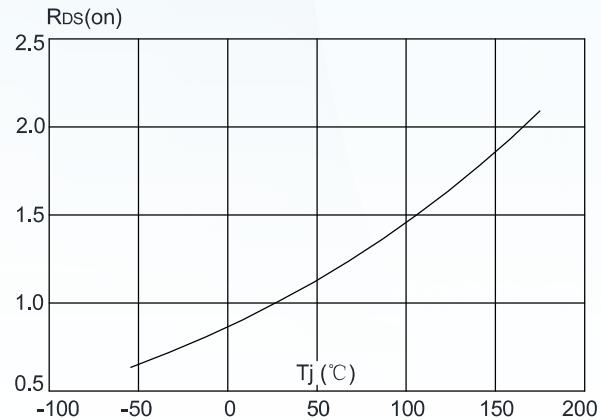
**Figure 6:** Capacitance Characteristics



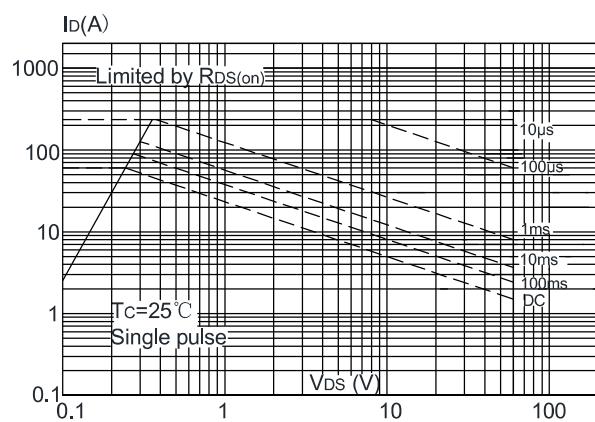
**Figure 7:** Normalized Breakdown Voltage vs. Junction Temperature



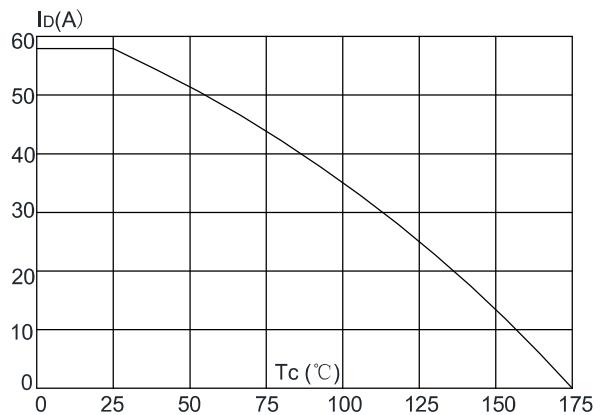
**Figure 8:** Normalized on Resistance vs. Junction Temperature



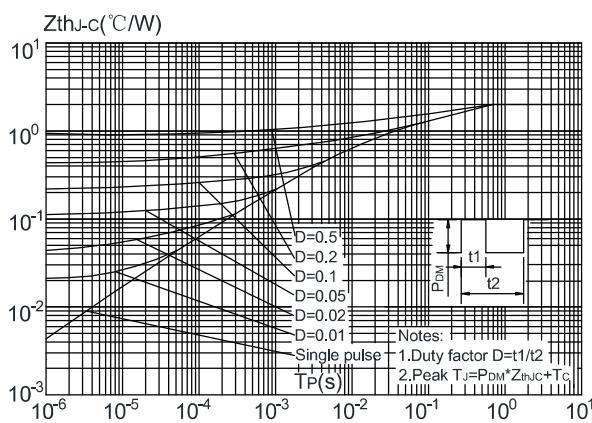
**Figure 9:** Maximum Safe Operating Area



**Figure 10:** Maximum Continuous Drain Current vs. Case Temperature



**Figure 11:** Maximum Effective Transient Thermal Impedance, Junction-to-Case



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